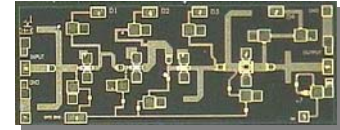


### Description

The iTR33001 is a 4-stage GaAs MMIC amplifier designed as a 33 GHz Buffer Amplifier for use in the LO chain of point to point radios, point to multi- point communications, LMDS, and other millimeter wave applications. In conjunction with other iTerra amplifiers, multipliers and mixers it forms part of a complete 38 GHz transmit/receive chipset. The iTR33001 utilizes iTerra's 0.25 $\mu$ m power PHEMT process and is sufficiently versatile to serve in a variety of medium power amplifier applications.

### Features

- ❖ 4 mil substrate
- ❖ Small-signal gain 24 dB (typ.)
- ❖ Saturated power out 19 dBm (typ.)
- ❖ Voltage detector included to monitor Pout
- ❖ Chip size 3.2 mm x 1.2 mm x 100  $\mu$ m



### Absolute Ratings

Parameter	Symbol	Value	Units
Positive DC voltage (+4 V Typical)	Vd	+6	Volts
Negative DC voltage	Vg	-2	Volts
Simultaneous (Vd - Vg)	Vdg	8	Volts
Positive DC Current	I <sub>D</sub>	173	mA
RF Input Power (from 50 $\Omega$ source)	P <sub>IN</sub>	+8	dBm
Operating Baseplate Temperature	T <sub>C</sub>	-30 to +85	$^{\circ}$ C
Storage Temperature Range	T <sub>stg</sub>	-55 to +125	$^{\circ}$ C
Thermal Resistance (Channel to Backside)	R <sub>jc</sub>	130	$^{\circ}$ C/W

### Electrical Characteristics

(At 25 $^{\circ}$ C),  
50  $\Omega$  system,  
Vd=+4 V,  
Quiescent Current  
Idq=112 mA

Parameter	Min	Typ	Max	Unit
Frequency Range	32		35	GHz
Gate Supply Voltage (Vg) <sup>1</sup>		-0.2		V
Gain Small Signal (Pin= -15 dBm)	20	24		dB
Gain Variation vs. Frequency		2.0		dB
Power Output Saturated: (Pin=+1 dBm)	17	19		dBm
Drain Current at Psat		120		mA

Parameter	Min	Typ	Max	Unit
Power Added Efficiency (PAE): at Psat		15		%
Input Return Loss (Pin=-15 dBm)		12		dB
Output Return Loss (Pin=-15 dBm)		12		dB
DC Detector Voltage at Pout=18 dBm		1.0		V

**Note:**

1. Typical range of gate voltage is -0.5 to 0V to set Idq of 112 mA.

### Application Information

**CAUTION: THIS IS AN ESD SENSITIVE DEVICE.**

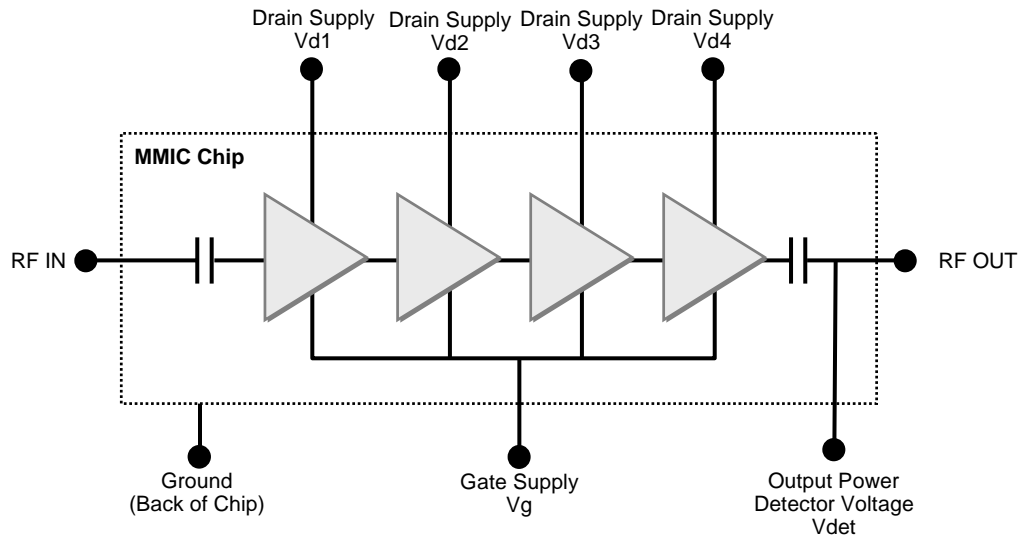
Chip carrier material should be selected to have GaAs compatible thermal coefficient of expansion and high thermal conductivity such as copper molybdenum or copper tungsten. The chip carrier should be machined, finished flat, plated with gold over nickel and should be capable of withstanding 325°C for 15 minutes.

Die attachment should utilize Gold/Tin (80/20) eutectic alloy solder and should avoid hydrogen environment for PHEMT devices. Note that the backside of the chip is gold plated and is used as RF and DC ground.

These GaAs devices should be handled with care and stored in dry nitrogen environment to prevent contamination of bonding surfaces. These are ESD sensitive devices and should be handled with appropriate precaution including the use of wrist grounding straps. All die attach and wire/ribbon bond equipment must be well grounded to prevent static discharges through the device.

Recommended wire bonding uses 3 mils wide and 0.5 mil thick gold ribbon with lengths as short as practical allowing for appropriate stress relief. The RF input and output bonds should be typically 0.012" long corresponding to a typical 2 mil gap between the chip and the substrate material.

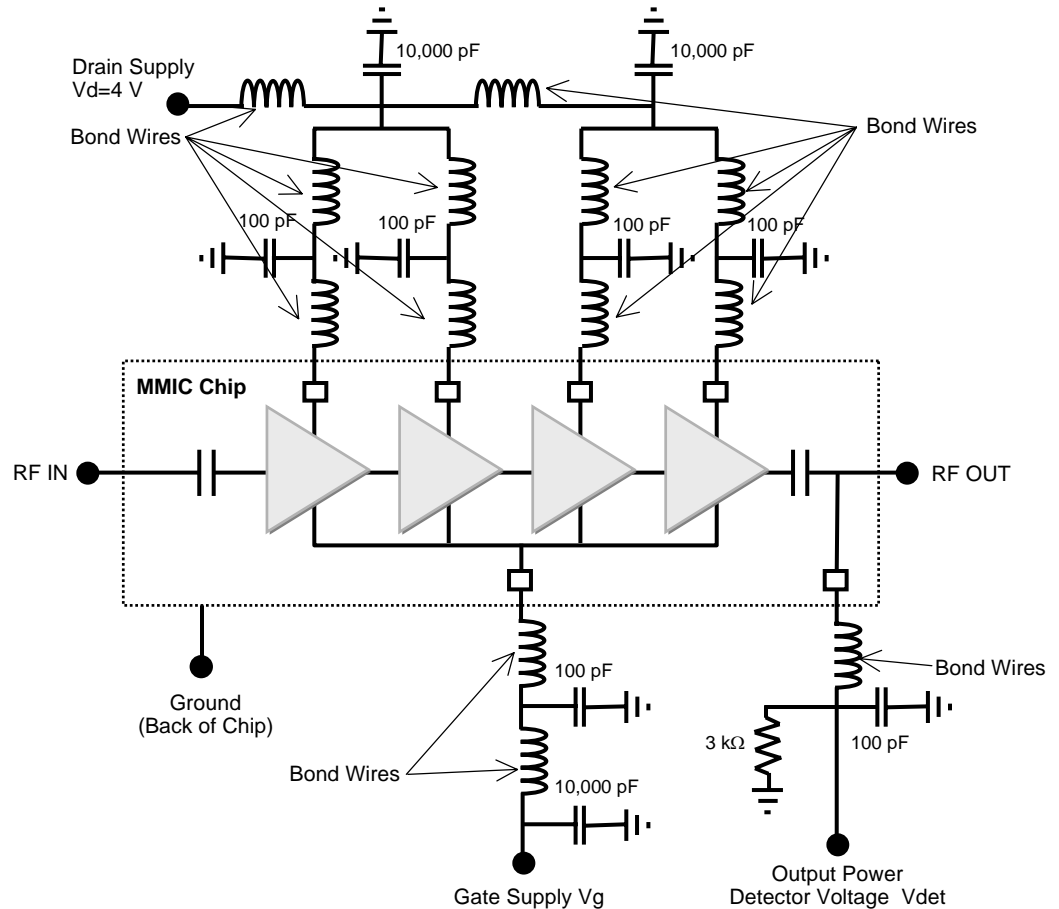
**Figure 1**  
Functional Block Diagram



**Note:**

Detector delivers > 0.1 V DC into 3k  $\Omega$  load resistor for >+18 dBm output power. If output power level detection is not desired, do not connect to detector bond pad.

**Figure 2**  
Schematic of  
Application Circuit



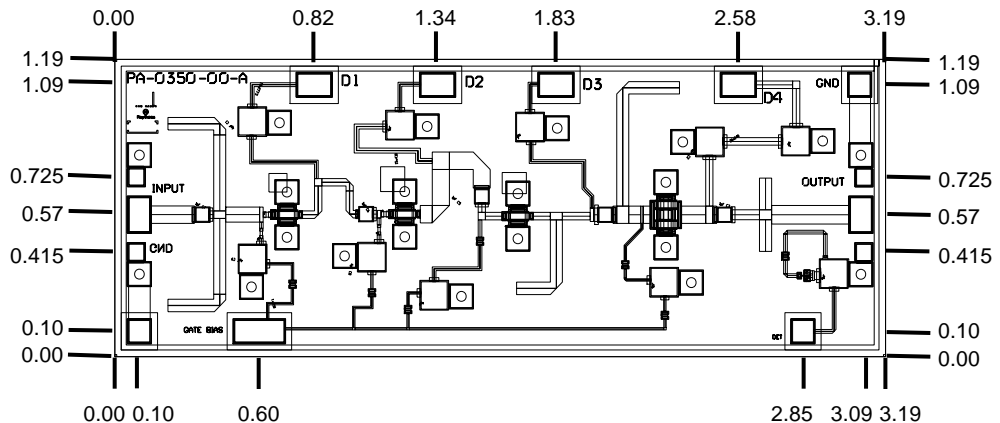
**Note:**

Detector delivers > 0.1 V DC into 3kΩ load resistor for >>+18dBm output power. If output power level detection is not desired, do not connect to detector bond pad.

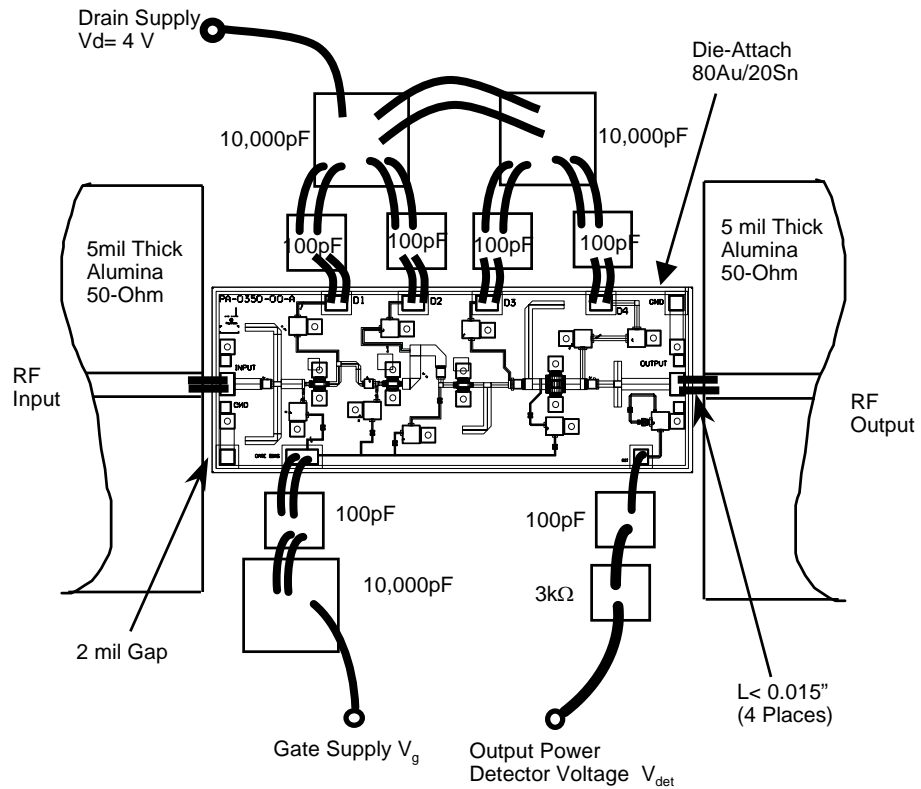
**Figure 3**  
Chip layout and  
Bond Pad Locations

Chip Size is  
3.19 mm x 1.19 mm  
x 100 μm.  
Back of chip is  
RF and DC ground

Dimensions in mm



**Figure 4**  
Recommended  
Assembly Diagram



**Note:**  
Use 0.003" by 0.0005" Gold Ribbon for bonding. RF input and output bonds should be less than 0.015" long with stress relief.

### Test Procedure

for biasing and  
operation

**CAUTION: LOSS OF GATE VOLTAGE (VG) WHILE DRAIN VOLTAGE (VD) IS PRESENT MAY DAMAGE THE AMPLIFIER CHIP.**

The following sequence must be followed to properly test the amplifier.

**Step 1:** Turn off RF input power.

**Step 2:** Connect the DC supply grounds to the grounds of the chip carrier. Slowly apply negative gate bias supply voltage of -1.5 V to  $V_g$ .

**Step 3:** Slowly apply positive drain bias supply voltage of +4 V to  $V_d$ .

**Step 4:** Adjust gate bias voltage to set the quiescent current of  $I_{dq}=112$  mA.

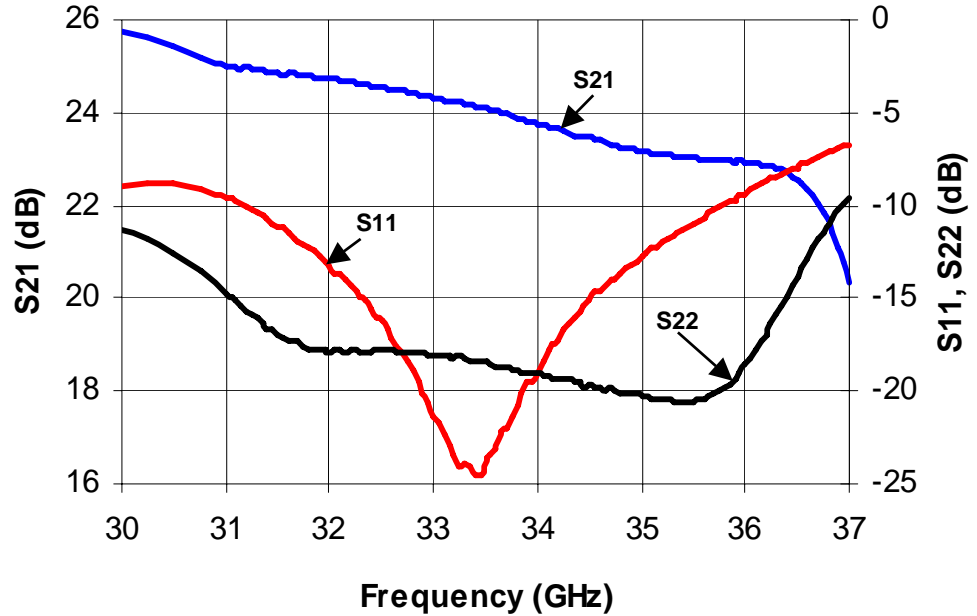
**Step 5:** After the bias condition is established, RF input signal may now be applied at the appropriate **frequency band**.

**Step 6:** Follow turn-off sequence of:

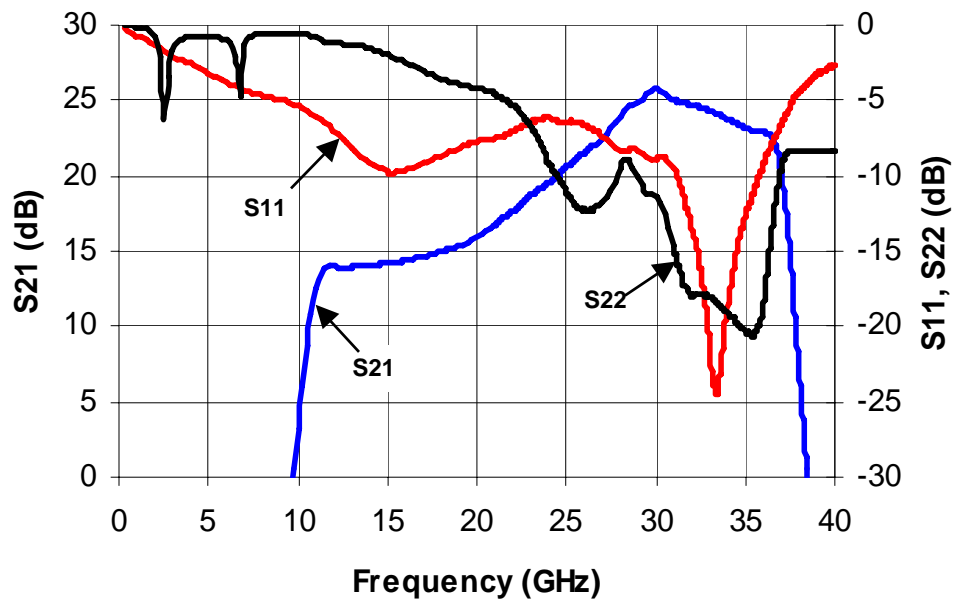
- (i) Turn off RF input power,
- (ii) Turn down and off drain voltage ( $V_d$ ),
- (iii) Turn down and off gate bias voltage ( $V_g$ ).

Performance  
Data

**iTR33001 33 GHz BA, Typical Small Signal Performance  
50  $\Omega$  Fixture Measurements,  $V_d=4$  V,  $I_{dq}=112$  mA,  $T=25$   $^{\circ}$ C**

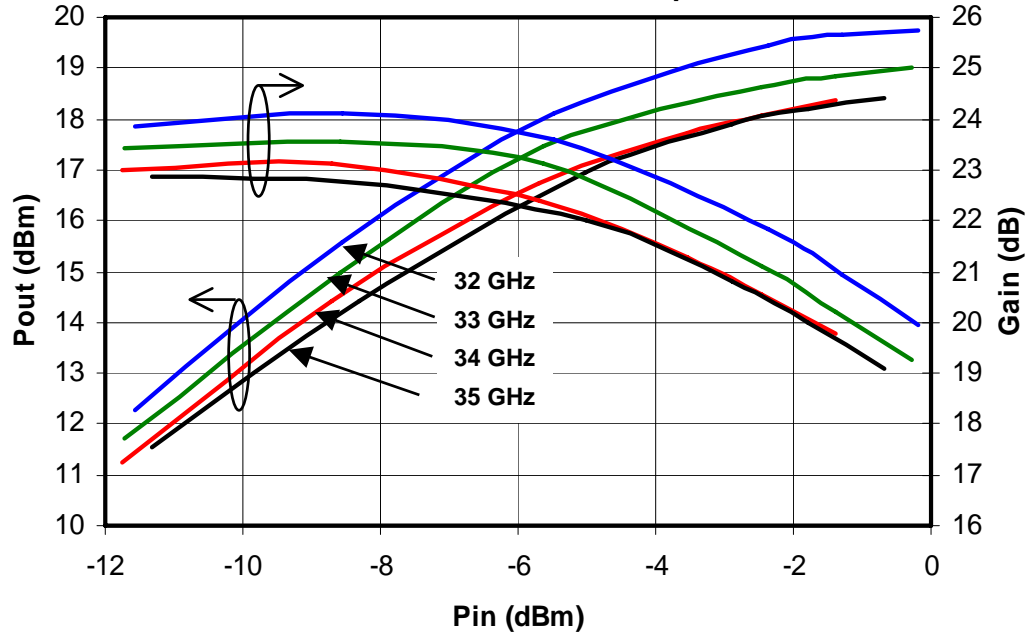


**iTR33001 33 GHz BA, Typical Small Signal Performance  
50  $\Omega$  Fixture Measurements,  $V_d=4$  V,  $I_{dq}=112$  mA,  $T=25$   $^{\circ}$ C**



Performance  
Data

iTR33001 33 GHz BA, Power Output and Gain Vs. Power In  
50  $\Omega$  Fixture Measurements,  $V_d=4$  V,  $I_{dq}=112$  mA,  $T=25$   $^{\circ}$ C



iTR33001 33 GHz BA, Power Output and Gain at 3 dB Compression Vs.  
Frequency and Temperature, 50  $\Omega$  Fixture Measurements,  $V_d=4$  V,  $I_{dq}=112$  mA

